

Search Notes

Application/Control No.

10/768,783

Examiner

Tse Chen

Applicant(s)/Patent under
R examination

LEE, CHANG-HWA

Art Unit

2116

SEARCHED

| Class | Subclass | Date | Examiner |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

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